

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	3	((flip adj chip) and ((test\$6 adj pad) with peripheral) and (bond\$5 adj pad) and ((trace or conductive) adj line)).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/22 14:08
L2	2	((flip adj chip) and ((test\$6 adj pad) with peripheral) and (bond\$5 adj pad) and ((trace or conductive) adj line)).clm.	US-PGPUB	OR	ON	2006/01/22 14:08
S1	2164	(257/778).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/05 10:26
S6	375	257/778.ccls. and (flip adj chip) and pad and test\$6 and @ad<="20030528"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/05 10:38
S7	297	257/778.ccls. and (flip adj chip) and pad and test\$6 and @ad<="20030528"	USPAT	OR	ON	2004/12/13 08:53
S12	6	(("5132757") or ("5766969") or ("6083846") or ("6127212") or ("6258680") or ("20040173794")). PN.	US-PGPUB; USPAT	OR	OFF	2004/12/13 11:05
S13	2	257/778.ccls. and (flip adj chip) and pad and test\$6 and (trace adj line) and @ad<="20030528"	USPAT	OR	ON	2004/12/13 08:54
S14	26	"257"/\$.ccls. and (flip adj chip) and pad and test\$6 and (trace adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 09:48
S15	0	("257"/\$.ccls. with (flip adj chip) with pad with (test\$6 adj pad) with (trace adj line)) and @ad<="20030528"	USPAT	OR	ON	2004/12/13 08:55
S16	0	(semiconductor with (flip adj chip) with pad with (test\$6 adj pad) with (trace adj line)) and @ad<="20030528"	USPAT	OR	ON	2004/12/13 08:55
S17	0	("438"/\$.ccls. with (flip adj chip) with pad with (test\$6 adj pad) with (trace adj line)) and @ad<="20030528"	USPAT	OR	ON	2005/10/20 14:05

S18	26	"257"/\$.ccls. and (flip adj chip) and pad and test\$6 and (trace adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:03
S19	12	"438"/\$.ccls. and (flip adj chip) and pad and test\$6 and (trace adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:03
S20	0	"438"/\$.ccls. and (flip adj chip adj pad) and test\$6 and (trace adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:03
S21	0	"438"/\$.ccls. and (flip adj chip adj pad) and (test\$6 adj pad) and (conductive adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:04
S22	4	"257"/\$.ccls. and (flip adj chip adj pad) and (test\$6 adj pad) and (conductive adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:05
S23	4	semiconductor and (flip adj chip adj pad) and (test\$6 adj pad) and (conductive adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:04
S24	0	("257"/\$.ccls. with (flip adj chip)) and (pad) and (test\$6 adj pad) and (conductive adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:06
S25	0	("438"/\$.ccls. with (flip adj chip)) and (pad) and (test\$6 adj pad) and (conductive adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:06
S26	10	(semiconductor with (flip adj chip)) and (pad) and (test\$6 adj pad) and (conductive adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:06
S27	0	(semiconductor near (flip adj chip)) and (pad) and (test\$6 adj pad) and (conductive adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:06
S28	11	(semiconductor same (flip adj chip)) and (pad) and (test\$6 adj pad) and (conductive adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:06
S29	0	("438"/\$.ccls. with (flip adj chip)) and ((test\$6 adj pad) with peripheral) and (bond\$5 adj pad) and ((trace or conductive) adj line) and @ad<="20030528"	USPAT	OR	ON	2005/10/20 14:09

S30	0	("438"/\$.ccls. with (flip adj chip)) and ((test\$6 adj pad) with peripheral) and (bond\$5 adj pad) and ((trace or conductive) adj line) and @ad<="20030528"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:08
S31	0	(semiconductor with (flip adj chip)) and ((test\$6 adj pad) with peripheral) and (bond\$5 adj pad) and ((trace or conductive) adj line) and @ad<="20030528"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:08
S32	0	("257"/\$.ccls. with (flip adj chip)) and ((test\$6 adj pad) with peripheral) and (bond\$5 adj pad) and ((trace or conductive) adj line) and @ad<="20030528"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:08
S33	1	(flip adj chip) and ((test\$6 adj pad) with peripheral) and (bond\$5 adj pad) and ((trace or conductive) adj line) and @ad<="20030528"	USPAT	OR	ON	2005/10/20 14:10
S34	28881	(flip adj chip)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:11
S35	2	(flip adj chip) and ((test\$6 adj pad) with peripheral) and (bond\$5 adj pad) and ((trace or conductive) adj line) and @ad<="20030528"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/22 14:08
S36	44	S34 and ((test\$4 adj pad) with peripheral)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:12
S37	38	S36 and (bond\$5 adj pad)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:12

S38	3	S37 and ((trace or conductive) adj line)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:13
S39	5	((("6674159") or ("6803659"))).PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 14:32
S40	39	(micron.as.) and (test adj probe) and (flip adj chip)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/21 09:05
S58	4	((("5,985,687") or ("4,848,272") or ("5,374,564") or ("5,835,521"))).PN.	USPAT	OR	OFF	2005/10/21 13:23
S59	1	("6893979").PN.	USPAT	OR	OFF	2005/10/21 13:55
S60	15	("4980307" "5578848" "5674788" "5861651" "5880040" "6015997" "6017791" "6087236" "6096656" "6100160" "6110842" "6136654" "6140024" "6372581" "6444592").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/21 13:24
S61	15	("4980307" "5578848" "5674788" "5861651" "5880040" "6015997" "6017791" "6087236" "6096656" "6100160" "6110842" "6136654" "6140024" "6372581" "6444592").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/21 13:34
S62	1	("6503846").PN.	USPAT	OR	OFF	2005/10/21 13:35
S63	3	((("6136654") or ("6444592") or ("4980307"))).PN.	USPAT	OR	OFF	2005/10/21 13:55